

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2891
Serial No. : 09/995,549 Examiner : Douglas M. Menz
Filed : November 27, 2001 Confirmation No.: 1184
Title : SEMICONDUCTOR THIN FILM, SEMICONDUCTOR DEVICE AND
MANUFACTURING METHOD THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST FOR INITIALED PTO FORM 1449

Upon reviewing the file, applicants noted that they have not received an initialed copy of the enclosed PTO Form 1449 that accompanied an information disclosure statement filed December 10, 2004.

Applicants' records show that this information disclosure statement complied with 37 CFR 1.97. Thus, we respectfully request that the examiner initial and return this form as soon as possible. Note, applicants must pay the issue fee by June 22, 2006, so the examiner's prompt attention to this matter would be appreciated.

Respectfully submitted,

Date: 5/4/06



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-124003	Application No. 09/995,549
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date November 27, 2001	Group Art Unit 2825

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,576,556	11/19/1996	Takemura et al.			08/16/1994
	AB	5,648,277	07/15/1997	Zhang et al.			11/02/1994
	AC	5,923,968	07/13/1999	Yamazaki et al.			09/08/1995
	AD	5,962,897	10/05/1999	Takemura et al.			06/30/1997
	AE	6,218,678 B1	04/17/2001	Zhang et al.			03/11/1997
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AR	
	AS	
	AT	
	AU	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	